

## DESCRIPTION

The CHD408L is a family of low voltage, low power 4Mbit static RAMs organized as 512K-words by 8-bit, designed with Cascade's patent pending SuperT-SRAM™ technology, fabricated with low-power 0.18μm process technology.

The CHD408LVS is designed specifically for low-power applications such as mobile cellular phones, personal digital assistants and other battery-operated products.

CHD408LVS -55,70 is packaged in sTSOP-I packages, with normal and reverse lead-bending. sTSOP-I packages are available in dimensions of 8x12mm and 8x20mm.

## FEATURES

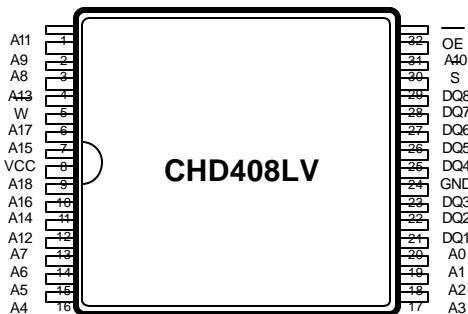
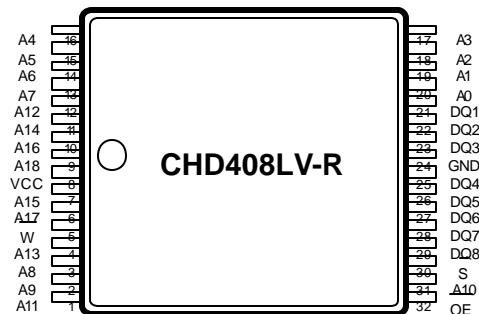
- Low power
  - Low active and standby power for hand-held applications.
  - Single power supply.
- High Performance
  - 55ns or 70ns access time
- Compatibility
  - 100% compatible with JEDEC asynchronous SRAM.
  - No clocks, no refresh.
  - No timing restrictions.
  - No special power-up sequence requirement.
  - Direct TTL compatibility for all inputs and outputs.
- Technology
  - Designed with Cascade's patent pending SuperT-SRAM™ technology.
  - Fabricated with low-power 0.18μm process technology.
- Extended temperature range -40 ~ 85°C.

## PART NAME TABLE & KEY SPEC SUMMARY

Power Supply	Part Name	Max. Access Time @ 2.7V	Standby Icc Max @ 3.0V 85°C	Active Icc 3.0V 10MHz
2.7V ~ 3.6V	CHD408LVx-70	70ns	35 μA	8mA
3.0V ~ 3.6V	CHD408LVx-55	55ns	35 μA	8mA

## PART SELECTION TABLE

Part Name	Package	Lead Bending
CHD408LVS-55,70	8x12mm STSOP-I	Normal
CHD408LVS-55,70-R	8x12mm STSOP-I	Reverse
CHD408LVW-55,70	8x20mm STSOP-I	Normal
CHD408LVW-55,70-R	8x20mm STSOP-I	Reverse

**PIN CONFIGURATION**
**(TOP VIEW)**

**32 Pin sTSOP(I)**
**(TOP VIEW)**

**Reverse 32 Pin sTSOP(I)**

Pin	Function
A0~A18	Address input
DQ1 ~ DQ8	Data input / output
<u>S</u>	Chip select input
<u>W</u>	Write control input
<u>OE</u>	Output enable input
VCC	Power supply
GND	Ground supply

## FUNCTIONAL DESCRIPTION

CHD408LVS -55/70(-R) is organized as 512K-words by 8-bit. These devices operate on a single power supply, and are directly TTL compatible to both input and output. The design uses fully asynchronous static circuits, requiring no clocks, no refresh, and no special power-up sequence.

The operation modes are determined by a combination of the device control inputs  $\overline{S}$ ,  $\overline{W}$  and  $\overline{OE}$ . Each mode is summarized in the function table.

A write operation is executed whenever the low level  $\overline{W}$  overlaps with the low level  $\overline{S}$ . The address (A0~A18) must be set up before the write cycle and must be stable during entire cycle.

A read operation is executed by setting  $\overline{W}$  at a high level and  $\overline{OE}$  at a low level while  $\overline{S}$  is in an active state.

When setting  $\overline{S}$  at a high level, the chip is in a non-select mode. In this mode, the output stage is in a high-impedance state, allowing OR-tie with other chips.

When  $\overline{OE}$  is at a high level, the output stage is in a high-impedance state.

## FUNCTION TABLE

$\overline{S}$	$\overline{OE}$	$\overline{W}$	DQ1-8	Mode	Power
H	X <sup>(1)</sup>	X	Z <sup>(2)</sup>	Deselected	Standby
L	H	H	Z	Output disabled	Active
L	L	H	Data out	read	Active
L	X	L	Data in	write	Active

Notes : (1) X means don't-care, but must drive to either high or low.

(2) Z means high impedance state.

**ABSOLUTE MAXIMUM RATINGS**

Parameter	Value	Unit	Notes
VCC Power Supply Voltage	-0.4 to 4.6	V	
VI Input Voltage	-0.4* to VCC+0.5 (max 4.6)	V	* -3V for AC pulse (<30ns)
VO Output Voltage	0 to VCC	V	
PD Power Dissipation	0.5	W	
Tsolder Soldering Temperature	260	°C	
Tstor Storage Temperature	-65 to 150	°C	
Toper Operating Temperature	-40 to 85	°C	

**DC ELECTRICAL CHARACTERISTICS (T = -40 to 85°C)**

	Parameter	Conditions	Min	Typ	Max	Units
VCC	Power Supply Voltage		2.7/3.0	-	3.6	V
V <sub>IH</sub>	Input High Voltage		2.2	-	V <sub>CC</sub> +0.4	V
V <sub>IL</sub>	Input Low Voltage		-0.4*	-	0.6	V
V <sub>OH</sub>	High-Level Output Voltage	I <sub>OH</sub> =-1mA	V <sub>CC</sub> -0.4	-	-	V
V <sub>OL</sub>	Low-level Output Voltage	I <sub>O</sub> =2mA	-	-	0.4	V
I <sub>I</sub>	Input Leakage Current	V <sub>I</sub> =0~V <sub>CC</sub>	-	-	±1	µA
I <sub>O</sub>	Output Leakage Current	Output disabled. V <sub>I/O</sub> =0~V <sub>CC</sub>	-	-	±1	µA

\* -3V for AC pulse (&lt;= 30ns)

**POWER CONSUMPTION CHARACTERISTICS**

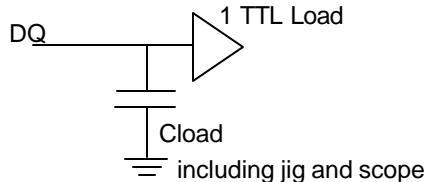
	Parameter	Conditions	Typ	Max (3.0V)	Max (3.6V)	Units
ICC1 10MHz	CMOS-Level Active Current at f=10MHz	Output open. All inputs = 0.2V or V <sub>CC</sub> -0.2V	-	8	10	mA
ICC1 1MHz	CMOS-Level Active Current at f=1MHz	Output open. All inputs = 0.2V or V <sub>CC</sub> -0.2V	-	2	3	mA
ICC2 10MHz	TTL-Level Active Current at f=10MHz	Output open. All inputs = V <sub>IL</sub> or V <sub>IH</sub>	-	9	11	mA
ICC2 1MHz	TTL-Level Active Current at f=1MHz	Output open. All inputs = V <sub>IL</sub> or V <sub>IH</sub>	-	3	4	mA
ISB1	Standby Current ( CMOS Level )	S = V <sub>CC</sub> -0.2V All other inputs = 0.2 or V <sub>CC</sub> -0.2V	-	35	60	µA
ISB2	Standby Current ( TTL Level )	S = V <sub>IH</sub> All other inputs = V <sub>IH</sub> or V <sub>IL</sub>	-	0.3	-	mA

**CAPACITANCE**

	Parameter	Min	Typ	Max	Notes
Cl	Input Capacitance			8pF	
Co	Output Capacitance			8pF	

**AC ELECTRICAL CHARACTERISTICS**
**(1) TEST CONDITIONS**

Parameter	Value	Notes
VCC	2.7-3.6V	
Input pulse level	VIH=2.4V, VIL=0.4V	
Input rise and fall time	5ns	
Reference level	VOH=VOL=1.5V	
Output loads	30pF	Plus one TTL input load

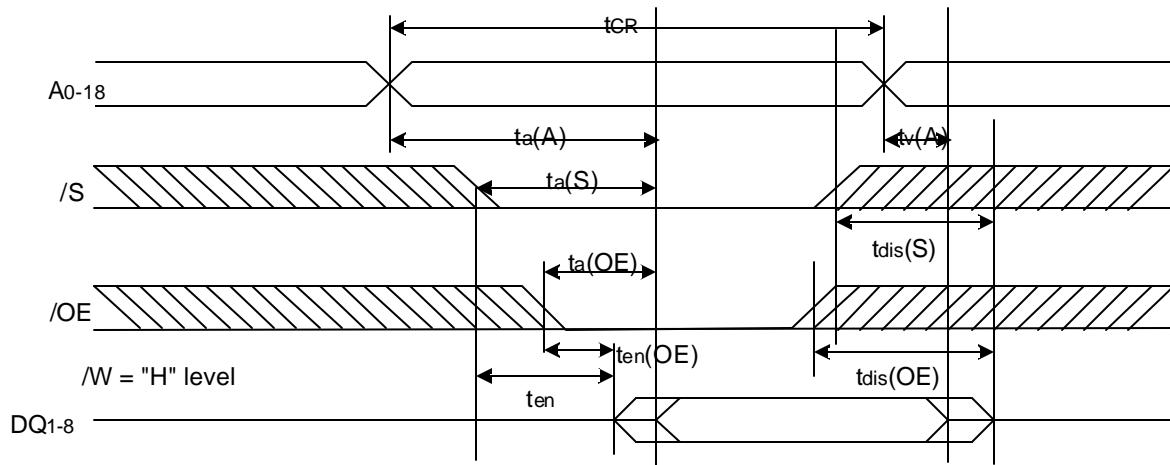
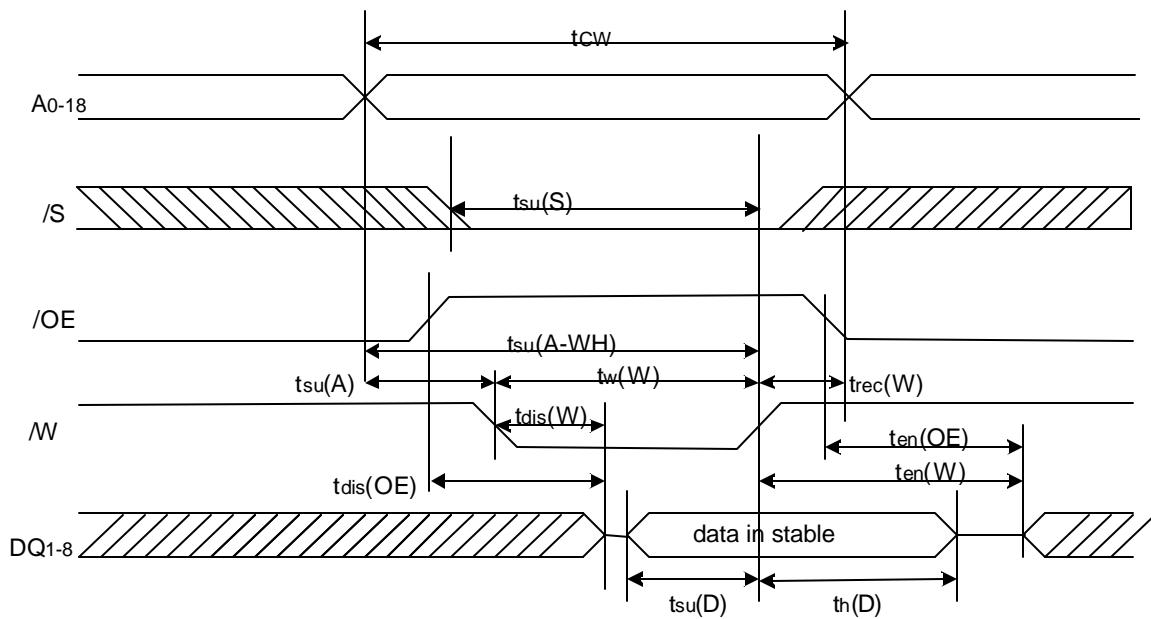

**(2) READ CYCLE**

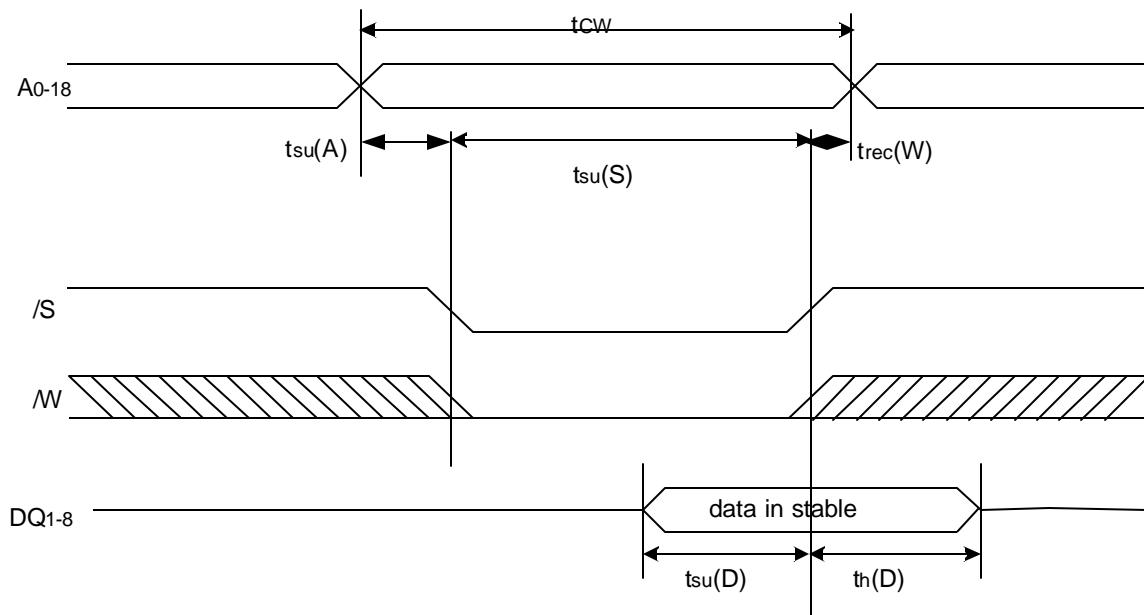
	Parameter	CHD408LVS-55(-R)		CHD408LVS-70(-R)	
		Min	Max	Min	Max
t <sub>CR</sub>	Read cycle time (ns)	55	-	70	-
t <sub>a(A)</sub>	Address access time (ns)	-	55	-	70
t <sub>a(S)</sub>	Chip select access time (ns)	-	55	-	70
t <sub>a(OE)</sub>	Output enable access time (ns)	-	25	-	35
t <sub>dis(S)</sub>	Output disable after /S (ns)	-	15	-	25
t <sub>ds(OE)</sub>	Output disable after /OE (ns)	-	15	-	25
t <sub>en(S)</sub>	Output enable after /S (ns)	5	-	5	-
t <sub>en(OE)</sub>	Output enable after /OE (ns)	5	-	5	-
t <sub>v(A)</sub>	Data valid time after address	10	-	10	-

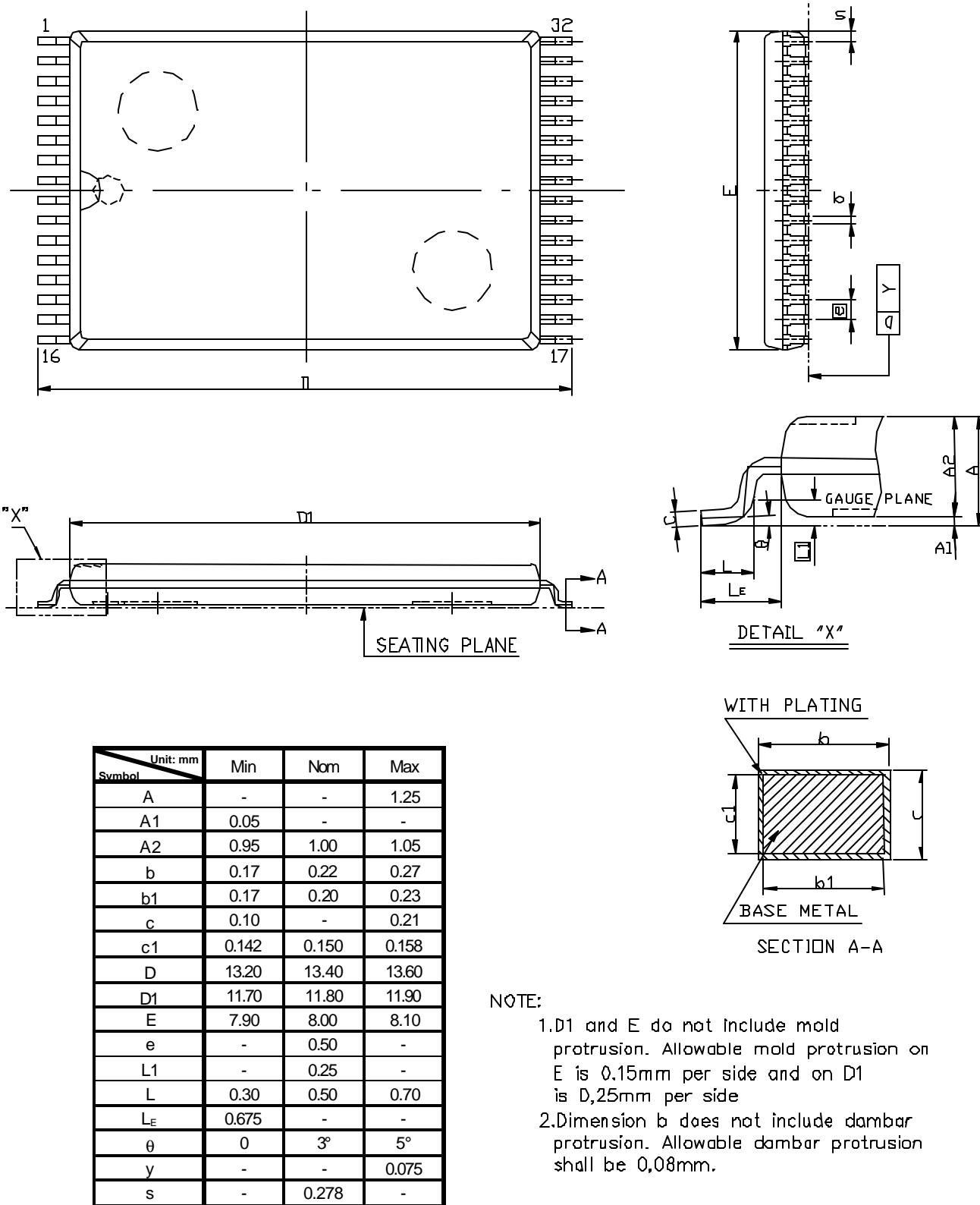
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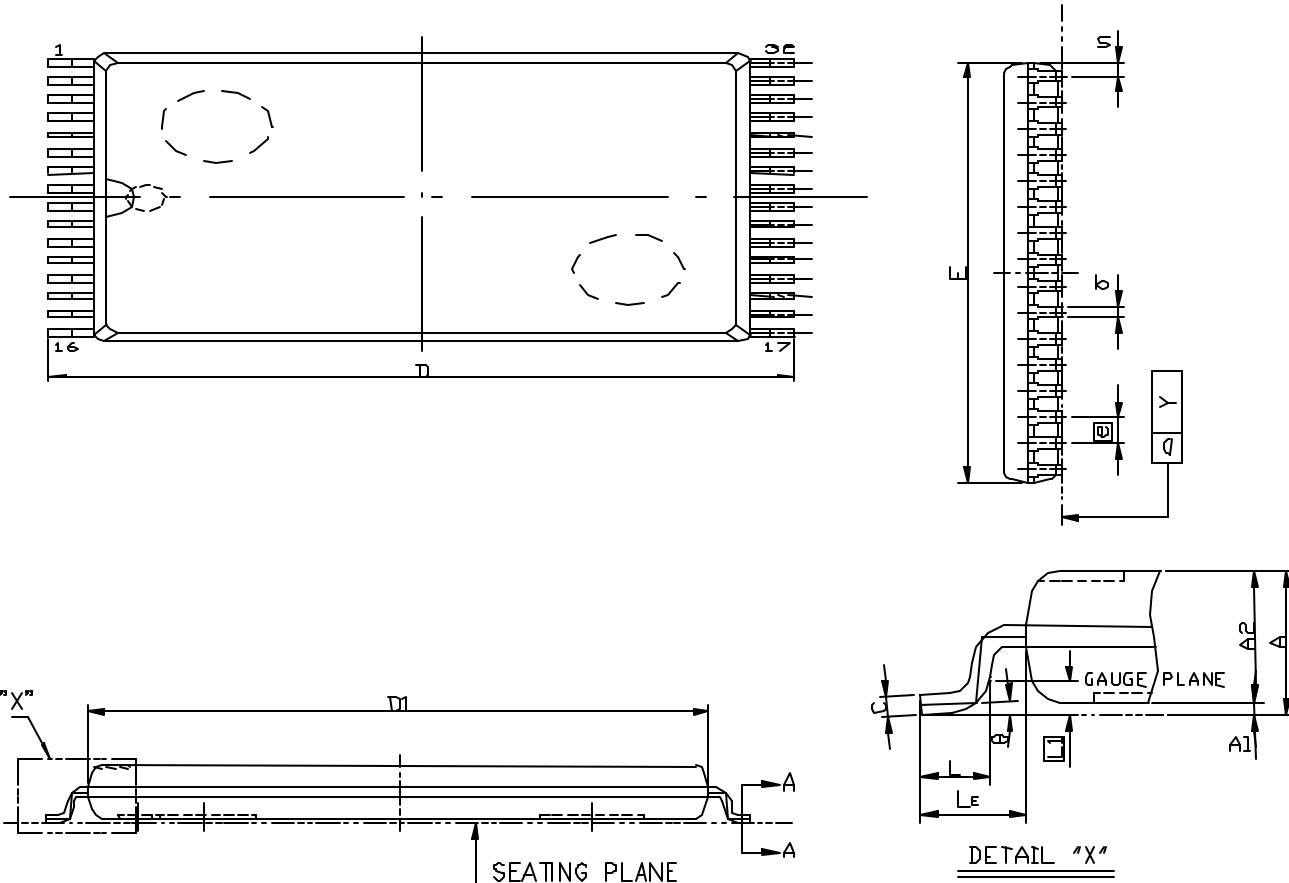
**(3) WRITE CYCLE**

	Parameter	CHD408LVS-55(-R)		CHD408LVS-70(-R)	
		Min	Max	Min	Max
$t_{CW}$	Write cycle time (ns)	55	-	70	-
$t_w(W)$	Write pulse width (ns)	45	-	55	-
$t_{SU}(A)$	Address setup time (ns)	0	-	0	-
$t_{SU}(A-WH)$	Add setup to Write high (ns)	45	-	55	-
$t_{SU}(S)$	Chip select setup time (ns)	45	-	55	-
$t_{SU}(D)$	Data setup time (ns)	25	-	25	-
$t_h(D)$	Data hold time (ns)	0	-	0	-
$t_{rec}(W)$	Write recovery time (ns)	0	-	0	-
$t_{dis}(W)$	Output disable after /W (ns)	-	25	-	25
$t_{dis}(OE)$	Output disable after /OE (ns)	-	25	-	25
$t_{en}(W)$	Output enable after /W (ns)	5	-	5	-
$t_{en}(OE)$	Output enable after /OE (ns)	5	-	5	-

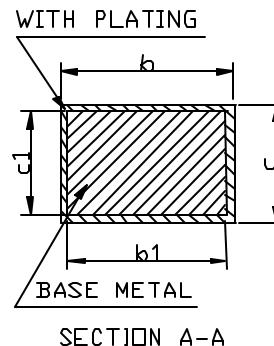
**(4) TIMING DIAGRAMS**
**READ CYCLE**

**WRITE CYCLE (/W control mode)**


**WRITE CYCLE (/S control mode)**


**32-Pin 8x12mm sTSOP-I Package Dimensions**


**32-Pin 8x20mm sTSOP-I Package Dimensions**


Symbol	Unit: mm	Min	Nom	Max
A		-	-	1.20
A1		0.05	-	0.15
A2		0.95	1.00	1.05
b		0.17	0.22	0.27
b1		0.17	0.20	0.23
c		0.10	-	0.16
c1		0.10	-	0.16
D		19.80	20.00	20.20
D1		18.20	18.40	18.60
E		7.80	8.00	8.20
e		-	0.50	-
L		0.50	0.60	0.70
L_E		0.80 REF		
θ		0	3°	5°
y		-	-	0.075
s		-	0.278	-


**NOTE:**

1. D1 and E do not include mold protrusion. Allowable mold protrusion on E is 0.15mm per side and on D1 is 0.25mm per side
2. Dimension b does not include dambar protrusion. Allowable dambar protrusion shall be 0.08mm.

**4M SuperT-SRAM™ CHD408LVx-55,70 Datasheet Revision History**

Preliminary 0.1	2/21/02	WC	Preliminary initial version
Rev 1.0	6/13/02	SC	Added more detailed DC parameters and test conditions; fixed some DC parameter numbers.  Added figure for output load
Rev 1.1	1/2/03	SC	Updated A17/A18 assignment to be consistent with industry convention.
Rev 2.0	3/20/03	JG	Added -55 grade
Rev 2.1	7/11/03	WC	Added 8x20mm TSOP-I package
Rev 2.2	7/22/03	WC	Renamed LVS-70W to LVW-70, to be consistent with naming convention.

- The information contained herein is subject to change without notice.